International Rectifier

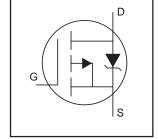
PD-95020A 120**NP**hF

IRFR9120NPbF IRFU9120NPbF

HEXFET® Power MOSFET



- P-Channel
- Surface Mount (IRFR9120N)
- Straight Lead (IRFU9120N)
- Advanced Process Technology
- Fast Switching
- Fully Avalanche Rated
- Lead-Free



$$V_{DSS} = -100V$$

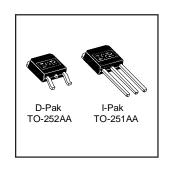
$$R_{DS(on)} = 0.48\Omega$$

$$I_{D} = -6.6A$$

Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The D-Pak is designed for surface mounting using vapor phase, infrared, or wave soldering techniques. The straight lead version (IRFU series) is for through-hole mounting applications. Power dissipation levels up to 1.5 watts are possible in typical surface mount applications.



Absolute Maximum Ratings

	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ -10V	-6.6	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ -10V	-4.2	A
I _{DM}	Pulsed Drain Current ①	-26	
P _D @T _C = 25°C	Power Dissipation	40	W
	Linear Derating Factor	0.32	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy®	100	mJ
I _{AR}	Avalanche Current®	-6.6	А
E _{AR}	Repetitive Avalanche Energy®	4.0	mJ
dv/dt	Peak Diode Recovery dv/dt ③	-5.0	V/ns
T _J	Operating Junction and	-55 to + 150	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		3.1	
$R_{\theta JA}$	Junction-to-Ambient (PCB mount)**		50	°C/W
R _{eJA}	Junction-to-Ambient		110	

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Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	· · · · · · · · · · · · · · · · · · ·						
	Parameter	Min.	Тур.	Max.	Units	Conditions	
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	-100			V	$V_{GS} = 0V, I_D = -250\mu A$	
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		-0.11		V/°C	Reference to 25°C, I _D = -1mA	
R _{DS(on)}	Static Drain-to-Source On-Resistance			0.48	Ω	$V_{GS} = -10V, I_D = -3.9A$ ④	
V _{GS(th)}	Gate Threshold Voltage	-2.0		-4.0	V	$V_{DS} = V_{GS}$, $I_D = -250\mu A$	
g _{fs}	Forward Transconductance	1.4			S	$V_{DS} = -50V, I_{D} = -4.0A$ ©	
I _{DSS}	Drain-to-Source Leakage Current			-25	μA	$V_{DS} = -100V, V_{GS} = 0V$	
1055	Drain to occinco Esanago Garrent			-250	"	V_{DS} = -80V, V_{GS} = 0V, T_{J} = 150°C	
lass	Gate-to-Source Forward Leakage			100	nA	$V_{GS} = 20V$	
I _{GSS}	Gate-to-Source Reverse Leakage			-100	''^	$V_{GS} = -20V$	
Qg	Total Gate Charge			27		I _D = -4.0A	
Q _{gs}	Gate-to-Source Charge			5.0	nC	V _{DS} = -80V	
Q _{gd}	Gate-to-Drain ("Miller") Charge			15		V_{GS} = -10V, See Fig. 6 and 13 \oplus \odot	
t _{d(on)}	Turn-On Delay Time		14			V _{DD} = -50V	
t _r	RiseTime		47			$I_{D} = -4.0A$	
t _{d(off)}	Turn-Off Delay Time		28		ns	$R_G = 12 \Omega$	
t _f	Fall Time		31			R_D =12 Ω , See Fig. 10 \oplus $\textcircled{6}$	
LD	Internal Drain Inductance		4.5			Between lead,	
LD.	Internal Drain Inductance		4.3		nH	6mm (0.25in.)	
L _S	Internal Source Inductance		7.5	_		from package	
						and center of die contact® s	
C _{iss}	Input Capacitance		350			V _{GS} = 0V	
C _{oss}	Output Capacitance		110		pF	$V_{DS} = -25V$	
C _{rss}	Reverse Transfer Capacitance		70			f = 1.0MHz, See Fig. 5®	

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions	
Is	Continuous Source Current			-6.6		MOSFET symbol	
	(Body Diode)	Diode)	-0.0	Α	showing the		
I _{SM}	Pulsed Source Current		200		integral reverse		
	(Body Diode) ①			-26		p-n junction diode.	
V _{SD}	Diode Forward Voltage			-1.6	V	$T_J = 25$ °C, $I_S = -3.9$ A, $V_{GS} = 0$ V ④	
t _{rr}	Reverse Recovery Time		100	150	ns	$T_J = 25^{\circ}C$, $I_F = -4.0A$	
Q _{rr}	Reverse Recovery Charge		420	630	nC	di/dt = 100A/µs ⊕ ⑥	
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)					

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Starting $T_J = 25^{\circ}C$, L = 13mH $R_G = 25\Omega$, $I_{AS} = -3.9A$. (See Figure 12)
- 4 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.
- $\tilde{\mathbb{S}}$ This is applied for I-PAK, L_S of D-PAK is measured between lead and center of die contact
- © Uses IRF9520N data and test conditions.
- ** When mounted on 1" square PCB (FR-4 or G-10 Material) . For recommended footprint and soldering techniques refer to application note #AN-994

International TOR Rectifier

IRFR/U9120NPbF

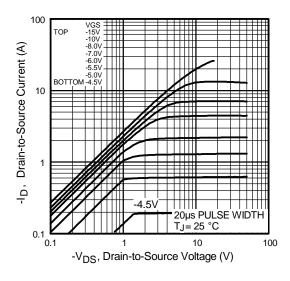


Fig 1. Typical Output Characteristics

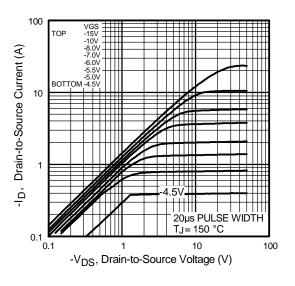


Fig 2. Typical Output Characteristics

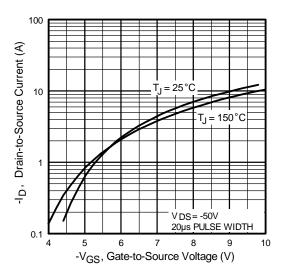


Fig 3. Typical Transfer Characteristics

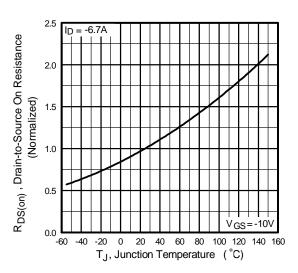


Fig 4. Normalized On-Resistance Vs. Temperature

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TOR Rectifier

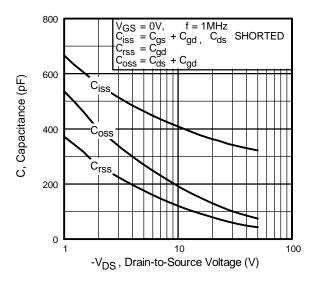
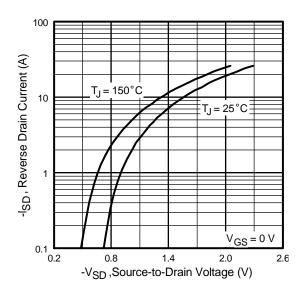
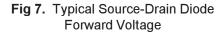


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage





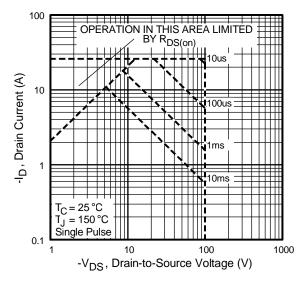


Fig 8. Maximum Safe Operating Area

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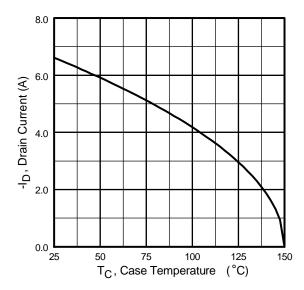


Fig 9. Maximum Drain Current Vs. Case Temperature

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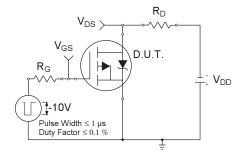


Fig 10a. Switching Time Test Circuit

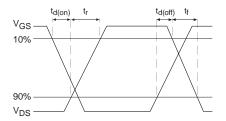


Fig 10b. Switching Time Waveforms

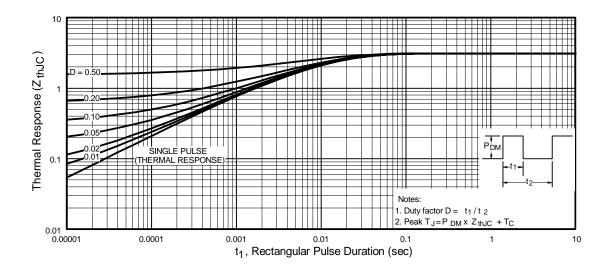


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

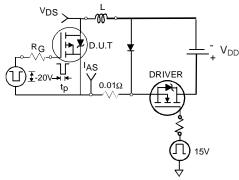


Fig 12a. Unclamped Inductive Test Circuit

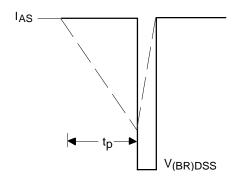


Fig 12b. Unclamped Inductive Waveforms

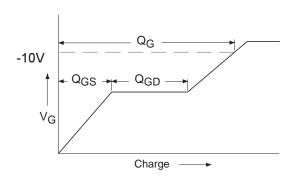


Fig 13a. Basic Gate Charge Waveform

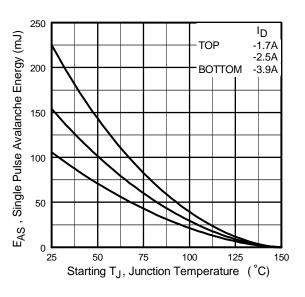


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

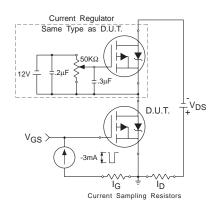
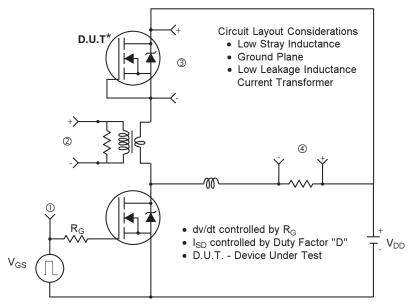
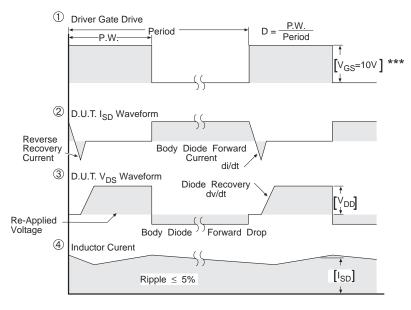


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



* Reverse Polarity of D.U.T for P-Channel



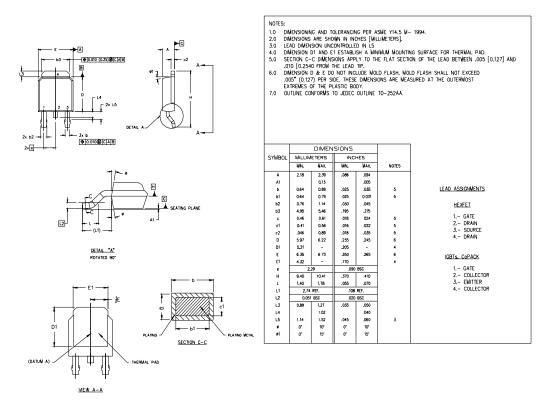
*** V_{GS} = 5.0V for Logic Level and 3V Drive Devices

Fig 14. For P-Channel HEXFETS

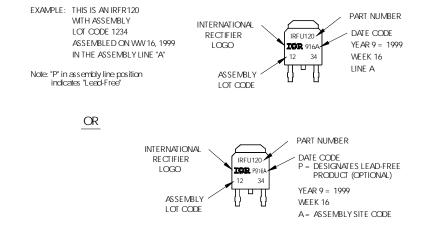
International TOR Rectifier

D-Pak (TO-252AA) Package Outline

Dimensions are shown in millimeters (inches)



D-Pak (TO-252AA) Part Marking Information



International IOR Rectifier

 \triangle E1

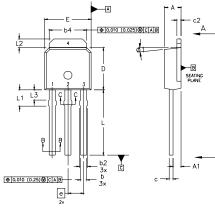
VIEW A-A

D1 🛕

IRFR/U9120NPbF

I-Pak (TO-251AA) Package Outline

Dimensions are shown in millimeters (inches)



- DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.
 DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
 DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED
 0.005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST
 EXTREMES OF THE PLASTIC BODY.
 THERMAL PAD CONTOUR OPTION WITHIN DIMENSION 64, L2, E1 & D1.
- LEAD DIMENSION UNCONTROLLED IN L3.

DIMENSION 61, 63 APPLY TO BASE METAL ONLY, OUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA.

DIMENSIONS

CONTROLLING DIMENSION : INCHES.

	SYMBOL	MILLIN	ETERS	INC	İ	
A1		MIN.	MAX.	MIN.	MAX.	NOTES
Α.	A	2,18	2.39	0.086	.094	
	A1	0.89	1,14	0.035	0.045	
	b	0.64	0.89	0.025	0.035	
	ь1	0.64	0,79	0.025	0.031	4
	b2	0,76	1,14	0.030	0.045	
	b3	0.76	1,04	0.030	0.041	
	b4	5.00	5.46	0.195	0.215	4
	c	0,46	0,61	0.018	0.024	
	c1	0.41	0,56	0.016	0.022	
	c2	.046	0.86	0.018	0.035	
	D	5.97	6.22	0.235	0.245	3, 4
	D1	5.21	-	0,205	-	4
	E	6,35	6,73	0,250	0,265	3, 4
-1	E1	4,32	-	0,170	-	4
ZA	e	2.	29	0.090	BSC	
% †	L	8.89	9.60	0,350	0.380	
¢1	L1	1,91	2,29	0,075	0,090	
*	L2	0.89	1,27	0,035	0.050	4
4	L3	1,14	1.52	0.045	0.060	5
4	ø1	o*	15*	0*	15*	

DATE CODE

WFFK 19

YEAR 9 = 1999

P = DESIGNATES LEAD-FREE PRODUCT (OPTIONAL)

A = ASSEMBLY SITE CODE

LEAD ASSIGNMENTS

HEXFET

- 1 GATE
- 2.- DRAIN 3.- SOURCE 4.- DRAIN

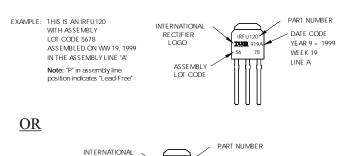
I-Pak (TO-251AA) Part Marking Information

RECTIFIER LOGO

ASSEMBLY LOT CODE

-(b, b2)-

-b1, b3 → SECTION A-A

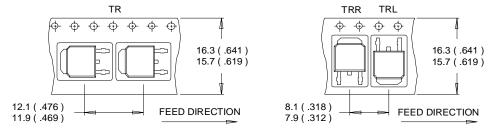


IRFU120

TOR.

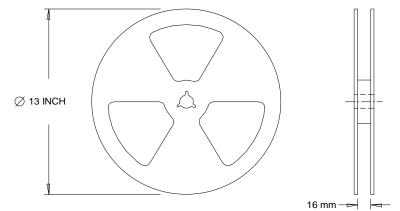
D-Pak (TO-252AA) Tape & Reel Information

Dimensions are shown in millimeters (inches)



NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:

1. OUTLINE CONFORMS TO EIA-481.

Data and specifications subject to change without notice.



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Note: For the most current drawings please refer to the IR website at: http://www.irf.com/package/

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